

U.S. Patent Application Serial No. 10/565,156  
Response to OA dated May 12, 2008

**AMENDMENTS TO THE CLAIMS:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

Claim 1 (Currently Amended): A probe comprising:

an almost rectilinear contact part which can come in contact with an electrode of an object to be measured almost perpendicularly, a tip end of the contact part being adapted to scrub the electrode; and

a base end continued to the contact part,

characterized in that said contact part further comprises a base part with the tip end formed of a first material having a first thermal expansion coefficient, and an almost rectilinear junction part which is formed of a second material having a second thermal expansion coefficient different from that of the first material base part and provided integrally and longitudinally along a widthwise end of the base part,

and in that said contact part is deformed in a direction almost perpendicular to the longitudinal direction of said base part due to respective thermal expansion of said base part and said junction part ~~at 85 to 125°C~~.

Claim 2 (Currently Amended): A probe comprising:

an almost rectilinear contact part which can come in contact with an electrode of an object

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to be measured almost perpendicularly, a tip end of the contact part being adapted to scrub the electrode; and

a base end continued to the contact part,

characterized in that said contact part further comprises a base part with the tip end which is formed of an elastic material and a junction part which is integrally provided at a widthwise end of said base part,

in that said junction part is formed of a shape memory alloy which can be expanded or contracted in a longitudinal direction of said base part ~~at 80 to 90°C,~~

and in that said contact part is deformed in a direction almost perpendicular to the longitudinal direction of said base part due to deformation of said junction part.